

M6200

Electrical, Optical & Thermal
Imaging & Test Systems

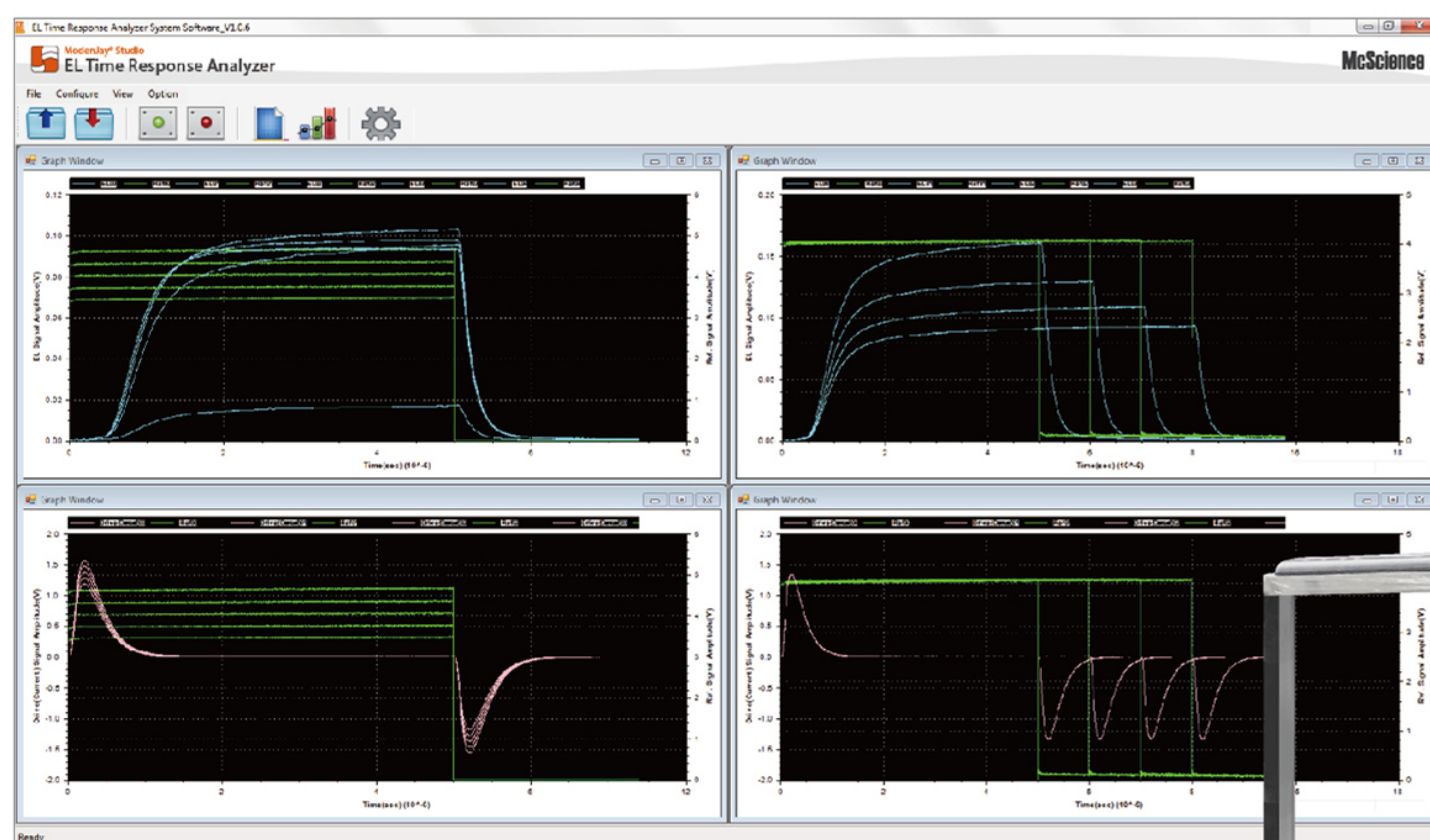
OLED Transient EL/PL Test System

High Accuracy and Enhanced Performance for Transient Response Measurement of OLED

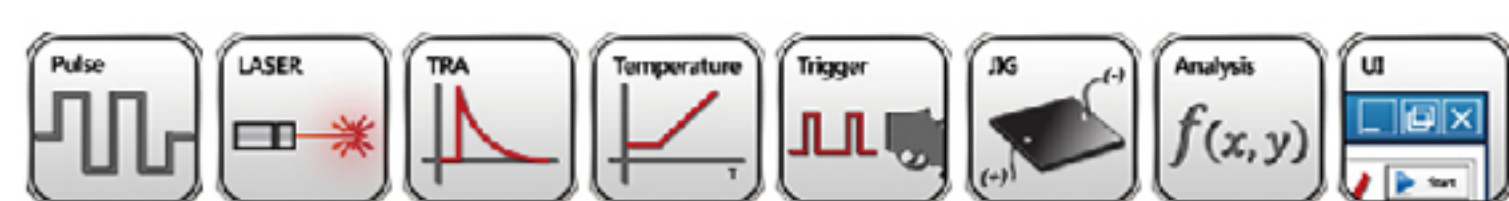
M6200 OLED Transient EL/PL Test System is designed to measure transient response characteristics of OLED device such as transient electroluminescence, time resolved photoluminescence. As excitation source, transient EL test system uses the electrical pulse generator, while time resolved PL test system uses the high speed pulse laser. It is useful tool to study charge carrier dynamics such as charge mobility, response time and carrier lifetime.

OLED + Transient Electroluminescence

Time Resolved Photoluminescence



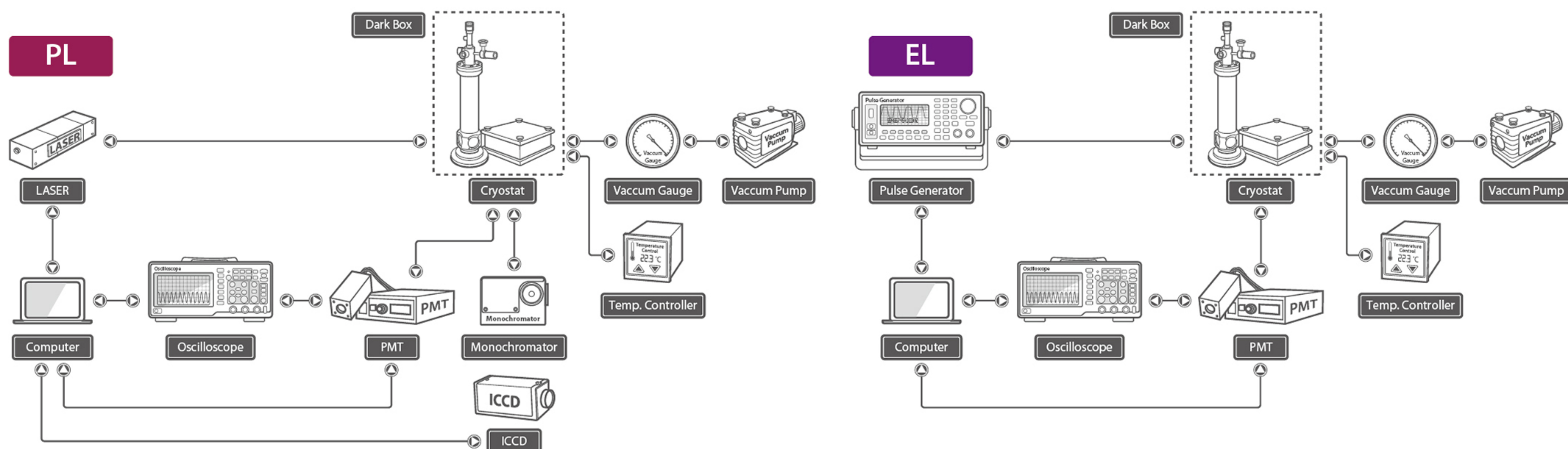
Transient Electroluminescence
Time Resolved Photoluminescence
Low Temperature Measurement
Spectroscopy Measurement



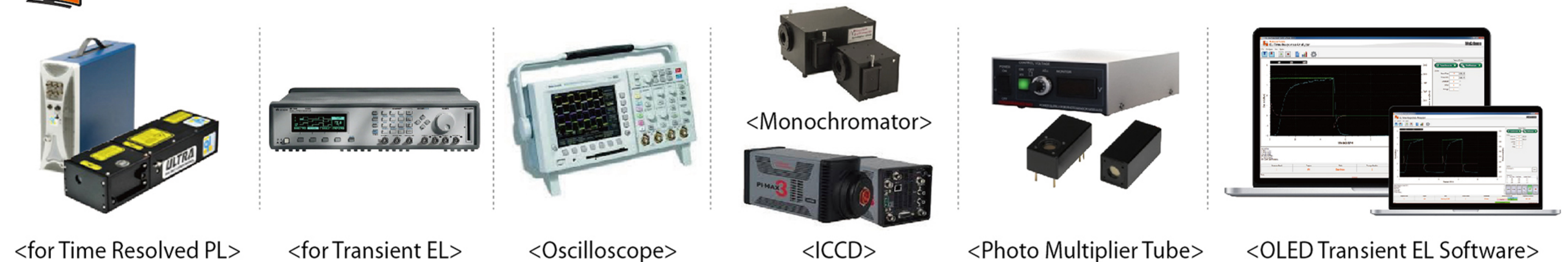
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System Configuration



System Components



System Specification

Product Name		M6200 OLED Transient EL/PL Test System
Function		Transient Electroluminescence Measurement (T-EL Option) Time Resolved Photoluminescence Measurement (T-PL Option)
Pulse Generator (for T-EL)	Frequency	1uHz ~ 10MHz
	Amplitude / DC Offset	1mVpp to 10Vpp into 50ohm / $\pm 5V$ into 50ohm
	Trigger	Single / Continuous / Burst Mode
Laser (for T-PL)	Type	Nd:Yag Pulse Laser
	Wavelength	355nm, 532nm, 1064nm
	Energy	8mJ@355nm, 25mJ@532nm, 50mJ@1064nm
	Pulse Duration	3-5ns @ 355nm, 3-5ns @ 532nm, 5-7ns @ 1064nm
Oscilloscope	Oscilloscope Bandwidth	500MHz
	Oscilloscope Sampling Rate	5GSa/s
Light Detector		Photo Multiplier Tube with 1nsec Rise Time
I-V Converter		50ohm Load Resistor or Preamplifier with 200MHz Bandwidth and 1.8ns Rise Time
Temperature Option		Cryostat System using Liquid Nitrogen (Temperature Range : 85K ~ 475K)